

Applicant: Ryuzo Iga et al.

Confirmation No.: 9935

Serial No.: 10/577,626

Att'y Docket No.: 14321.84

Filing Date: April 28, 2006

Art Unit: 2828

For: SEMICONDUCTOR OPTICAL DEVICE AND A METHOD OF FABRICATING THE SAME

INFORMATION DISCLOSURE CITATIONS MADE BY APPLICANTU.S. Patent Documents

Examiner Initial*	Document Number	Issue Date	Name
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___ 2	6,300,153 B1	10/09/2001	Koui
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___ 8	05-021891	01/29/1993	Japan	No
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(including author, title, pertinent pages, etc.)

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Initial*

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- ____ 21 Ryuzo Iga et al., *Ruthenium-Doped InP Buried 1.3 μm DFB Lasers on a P-Type Substrate*, 2004 International Conference on Indium Phosphide and Related Materials, Conference Proceedings, 16th IPRM, Kagoshima, Japan, May 31-June 4, 2004, pp. 742-745.
- ____ 22 Ryuzo Iga et al., *Directly Modulated 1.3 μm DFB Lasers with a Buried Heterostructure Using Ru-doped Semi-Insulating InP*, Technical Report of IEICE, EMD2004-43, CPM2004-69, OPE2004-126, LQE2004-41(2004-08), pp. 19-24 (only Abstract is attached).
- ____ 23 Ryuzo Iga et al., *Directly Modulated 1.3- μm DFB Laser with a Buried Structure Formed by Using Ru-doped Semi-insulating InP*, 31p-ZH-10, 2005 (all the document is translated).

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The reference designations "A1," "A2," etc. (referring to Applicant's reference 1, Applicant's reference 2, etc.) will be used by the Examiner in the same manner as Examiner's reference designations "A," "B," "C," etc. on Office Action Form PTO-1142.

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